

Form PTO-1449 (modified)

Atty. Docket No. 2096.001300/Serie: 6184 Serial No. 10/622,015

6. List of Patents and Publications for Applicant's  
 INFORMATION DISCLOSURE STATEMENT  
 (Use several sheets if necessary)

Applicant  
Cowles and Bollinger

Filing Date: July 17, 2003 Group: 1743

U.S. Patent Documents

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Foreign Patent Documents

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Other Art

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**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.

**Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

**Other Art (Including Author, Title, Date Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
MW	C1	Chen <i>et al.</i> , "Spectrophotometric Determination of Trace and Ultratrace Levels of Boron in Silicon and Chlorosilane Samples," <i>Fresenius J. Anal. Chem.</i> , 340:357-362, 1991.
MW	C2	Cowles and Bollinger, "Point-of-Use Sampling and Metal Analysis for Trichlorosilane," <i>SEMI Technical Symposium (STS): Innovations in Semiconductor Manufacturing</i> , July 2002.
MW	C3	Stolyarova and Orlova, "Trichlorosilane and Silicon Tetrachloride Sample Preparation for Trace Boron, Phosphorus, and Arsenic Determination," <i>J. Anal. Chem.</i> , 50(2):130-134, 1995.
MW	C4	Wei and Yang, "Determination of Phosphorus and Arsenic in Trichlorosilane by Electrothermal Vaporization-Inductively Coupled Plasma Mass Spectrometry with Prior Concentration by Cuprous Chloride," <i>Fresenius J. Anal. Chem.</i> , 353:167-170, 1995.
MW	C5	Presentation of POU Sampling and Metal Analysis of Trichlorosilane at SEMI Semiconductor Equipment and Materials International, July 2002.

EXAMINER:

/Maureen Wallenhorst/ (11/29/2006)

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.